PCN Number:		2018	20181005001.0		PCN Date:	October 08, 2018		2018
Tit	Title: Datasheet for DS90UB934-Q1							
Customer Contact: P		PCN I	PCN Manager			Dept:		Quality Services
Change Type:								
	Assembly Site			Design			Wafer	Bump Site
	Assembly Process			□ Data Sheet			Wafer	Bump Material
Assembly Materials			Part number change			Wafer	Bump Process	
Mechanical Specification			Test Site			Wafer	Fab Site	
Packing/Shipping/Labeling		ng	Test Proce	ess		Wafer	Fab Materials	
	☐ Wafer Fab Process							
Notification Details								

Description of Change:

Texas Instruments Incorporated is announcing an information only notification.

The product datasheet(s) is being updated as summarized below.

The following change history provides further details.



DS90UB934-Q1

SNLS507B - SEPTEMBER 2016-REVISED OCTOBER 2018

	nanges from Revision A (January 2017) to Revision B	Page
•	Added that unused GPIOs can be left open or floating	5
•	Added that PDB is internal pull down enabled	
•	Added description for selecting pull up resistor for OSS_SEL	5
•	Added description for selecting pull up resistor for OEN	5
•	Removed S, PD type for RES (pin 44)	6
•	Removed S, PD type for RES (pin 43) and added it must be tied to GND.	6
•	Added PDB test conditions for the LVCMOS IO voltage parameter in the Absolute Maximum Ratings table	7
•	Changed typical LVCMOS low-to-high transition time value from: 2.5 ns to: 2 ns	11
•	Changed maximum LVCMOS low-to-high transition time value from: 4 ns to: 3 ns	11
•	Changed typical LVCMOS high-to-low transition time value from: 2.5 ns to: 2 ns	
•	Changed maximum LVCMOS high-to-low transition time value from: 4 ns to: 3 ns	11
•	Changed receiver clock jitter test condition from: SSCG[3:0] = OFF to: SSCG[0] = OFF	
•	Changed deserializer period jitter test condition from: SSCG[3:0] = OFF to: SSCG[0] = OFF	11
•	Changed deserializer cycle-to-cycle clock jitter test condition from: SSCG[3:0] = OFF to: SSCG[0] = OFF	11
•	Changed input jitter symbol from: TOL _{JIT} to: T _{JIT}	12
•	Added reference to compatibility with DS90UB953-Q1/935-Q1 serializers	17
•	Added column for DS90UB953-Q1/935-Q1	20
•	Added clarification on input mode selection	20
•	Fixed typo in Figure 13 supply rail text	20
•	Changed pullup power supply node from VDDIO to V(I2C)	26
•	Removed pullup resistor recommendation	26
•	Updated description of clock frequency during BIST operation	31
•	Fixed typos in register maps	32

•	Updated register "TYPE" column per legend	32
•	Fixed typo in register name.	40
•	Added Power Over Coax section	
•	Updated return loss S11 values	56
•	Added STP typical connection diagram	
•	Updated recommendation for common ground plane	61
•	Updated recommendation for bypass capacitors	
•	Updated typical bypass capacitor value from 50uF to 47uF	62

The datasheet number will be changing.

Device Family	Change From:	Change To:
DS90UB934-Q1	SNLS507A	SNLS507B

These changes may be reviewed at the datasheet links provided.

http://www.ti.com/product/DS90UB934-Q1

Reason for Change:

To accurately reflect device characteristics.

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

No anticipated impact. This is a specification change announcement only. There are no changes to the actual device.

Changes to product identification resulting from this PCN:

None

Product Affected:

DS90UB934TRGZRQ1	DS90UB934TRGZTQ1	

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
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